MOSFET – N-Channel, SUPERFET II, FRFET

600 V, 37 A, 104 mΩ

FCH104N60F

Description

SUPERFET$^®$ II MOSFET is ON Semiconductor's brand−new high voltage super−junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low on−resistance and lower gate charge performance. This technology is tailored to minimize conduction loss, provide superior switching performance, dv/dt rate and higher avalanche energy. Consequently, SUPERFET II MOSFET is very suitable for the switching power applications such as PFC, server/telecom power, FPD TV power, ATX power and industrial power applications. SUPERFET II FRFET$^®$ MOSFET's optimized body diode reverse recovery performance can remove additional component and improve system reliability.

Features

- 650 V @ T_J = 150°C
- Typ. $R_{DS(on)}$ = 98 mΩ
- Ultra Low Gate Charge (Typ. Q_g = 107 nC)
- Low Effective Output Capacitance (Typ. $C_{oss(eff.)}$ = 109 pF)
- 100% Avalanche Tested
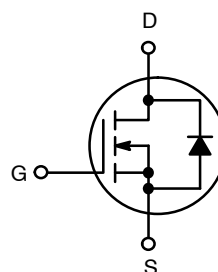- This Device is Pb−Free and is RoHS Compliant

Applications

- Telecom / Server Power Supplies
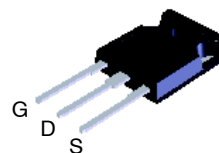- Industrial Power Supplies
- EV Charger
- UPS / Solar

ON Semiconductor$^®$

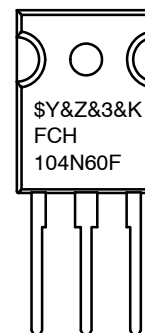www.onsemi.com

V_{DSS}	$R_{DS(ON)}$ MAX	I_D MAX
600 V	104 mΩ	37 A

N-Channel MOSFET

TO−247
CASE 340CK

MARKING DIAGRAM

$Y&Z&3&K
FCH
104N60F

$Y	= ON Semiconductor Logo
&Z	= Assembly Plant Code
&3	= Data Code (Year & Week)
&K	= Lot Code
FCH104N60F	= Specific Device Code

ORDERING INFORMATION

See detailed ordering and shipping information on page 2 of this data sheet.

FCH104N60F

ABSOLUTE MAXIMUM RATINGS ($T_C = 25°C$, Unless otherwise specified)

Symbol	Parameter		FCH104N60F	Unit
V_{DSS}	Drain to Source Voltage		600	V
V_{GSS}	Gate to Source Voltage	DC	±20	V
		AC (f > 1 Hz)	±30	
I_D	Drain Current	Continuous ($T_C = 25°C$)	37	A
		Continuous ($T_C = 100°C$)	24	
I_{DM}	Drain Current	Pulsed (Note 1)	111	A
E_{AS}	Single Pulsed Avalanche Energy (Note 2)		809	mJ
I_{AR}	Avalanche Current (Note 1)		6.8	A
E_{AR}	Repetitive Avalanche Energy (Note 1)		3.57	mJ
dv/dt	MOSFET dv/dt		100	V/ns
	Peak Diode Recovery dv/dt (Note 3)		50	
P_D	Power Dissipation	($T_C = 25°C$)	357	W
		Derate Above 25°C	2.85	W/°C
T_J, T_{STG}	Operating and Storage Temperature Range		−55 to +150	°C
T_L	Maximum Lead Temperature for Soldering, 1/8″ from Case for 5 s		300	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.
1. Repetitive rating: pulse-width limited by maximum junction temperature.
2. $I_{AS} = 6.8$ A, $R_G = 25$ Ω, starting $T_J = 25°C$.
3. $I_{SD} \leq 18.5$ A, di/dt ≤ 200 A/μs, $V_{DD} \leq 380$ V, starting $T_J = 25°C$.

THERMAL CHARACTERISTICS

Symbol	Parameter	FCH104N60F	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max.	0.35	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient, Max.	40	

PACKAGE MARKING AND ORDERING INFORMATION

Part Number	Top Marking	Package	Packing Method	Reel Size	Tape Width	Quantity
FCH104N60F	FCH104N60F	TO−247	Tube	N/A	N/A	30 Units

FCH104N60F

ELECTRICAL CHARACTERISTICS (T_C = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
OFF CHARACTERISTICS						
BV_{DSS}	Drain to Source Breakdown Voltage	V_{GS} = 0 V, I_D = 10 mA, T_J = 25°C	600	–	–	V
		V_{GS} = 0 V, I_D = 10 mA, T_J = 150°C	650	–	–	
$\Delta BV_{DSS}/\Delta T_J$	Breakdown Voltage Temperature Coefficient	I_D = 10 mA, Referenced to 25°C	–	0.67	–	V/°C
I_{DSS}	Zero Gate Voltage Drain Current	V_{DS} = 600 V, V_{GS} = 0 V	–	–	10	μA
		V_{DS} = 480 V, V_{GS} = 0 V, T_C = 125°C	–	16	–	
I_{GSS}	Gate to Body Leakage Current	V_{GS} = ±20 V, V_{DS} = 0 V	–	–	±100	nA
ON CHARACTERISTICS						
$V_{GS(th)}$	Gate Threshold Voltage	V_{GS} = V_{DS}, I_D = 250 μA	3	–	5	V
$R_{DS(on)}$	Static Drain to Source On Resistance	V_{GS} = 10 V, I_D = 18.5 A	–	98	104	mΩ
g_{FS}	Forward Transconductance	V_{DS} = 20 V, I_D = 18.5 A	–	47	–	S
DYNAMIC CHARACTERISTICS						
C_{iss}	Input Capacitance	V_{DS} = 100 V, V_{GS} = 0 V, f = 1 MHz	–	4475	5950	pF
C_{oss}	Output Capacitance		–	135	180	pF
C_{rss}	Reverse Transfer Capacitance		–	1.5	2.5	pF
C_{oss}	Output Capacitance	V_{DS} = 380 V, V_{GS} = 0 V, f = 1 MHz	–	75	–	pF
$C_{oss(eff.)}$	Effective Output Capacitance	V_{DS} = 0 V to 480 V, V_{GS} = 0 V	–	109	–	pF
$Q_{g(tot)}$	Total Gate Charge at 10 V	V_{DS} = 380 V, I_D = 18.5 A, V_{GS} = 10 V (Note 4)	–	107	139	nC
Q_{gs}	Gate to Source Gate Charge		–	25	–	nC
Q_{gd}	Gate to Drain "Miller" Charge		–	44	–	nC
ESR	Equivalent Series Resistance (G–S)	f = 1 MHz	–	0.87	–	Ω
SWITCHING CHARACTERISTICS						
$t_{d(on)}$	Turn-On Delay Time	V_{DD} = 380 V, I_D = 18.5 A, V_{GS} = 10 V, R_G = 4.7 Ω (Note 4)	–	34	78	ns
t_r	Turn-On Rise Time		–	24	58	ns
$t_{d(off)}$	Turn-Off Delay Time		–	98	206	ns
t_f	Turn-Off Fall Time		–	5	20	ns
SOURCE-DRAIN DIODE CHARACTERISTICS						
I_S	Maximum Continuous Source to Drain Diode Forward Current		–	–	37	A
I_{SM}	Maximum Pulsed Drain to Source Diode Forward Current		–	–	111	A
V_{SD}	Drain to Source Diode Forward Voltage	V_{GS} = 0 V, I_{SD} = 18.5 A	–	–	1.2	V
t_{rr}	Reverse Recovery Time	V_{GS} = 0 V, I_{SD} = 18.5, dI_F/dt = 100 A/μs	–	144	–	ns
Q_{rr}	Reverse Recovery Charge		–	0.91	–	μC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.
4. Essentially independent of operating temperature typical characteristics.

TYPICAL PERFORMANCE CHARACTERISTICS

Figure 1. On-Region Characteristics

Figure 2. Transfer Characteristics

Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

Figure 5. Capacitance Characteristics

Figure 6. Gate Charge Characteristics
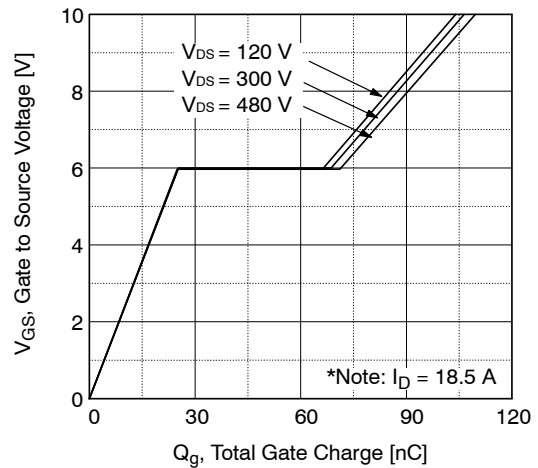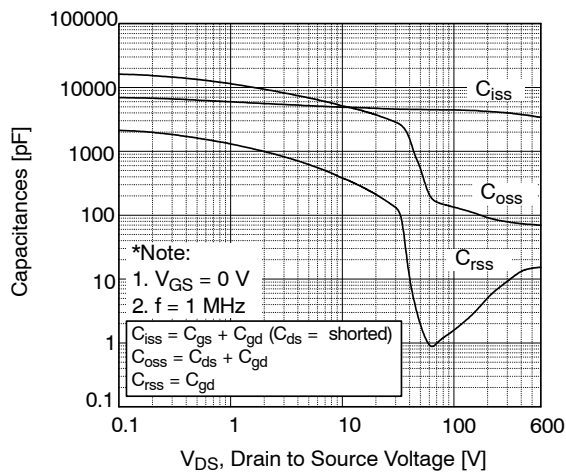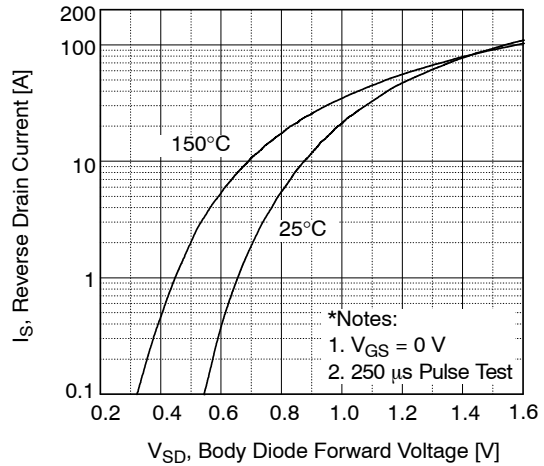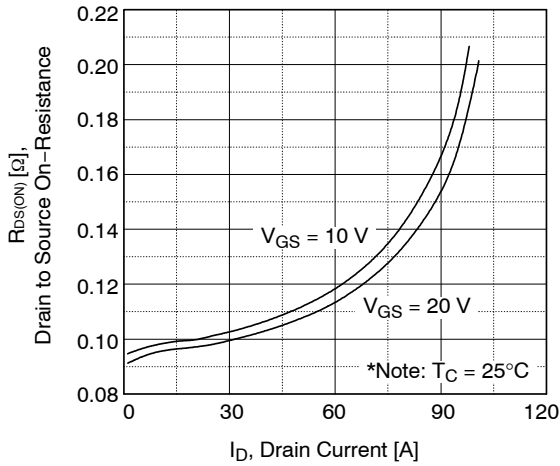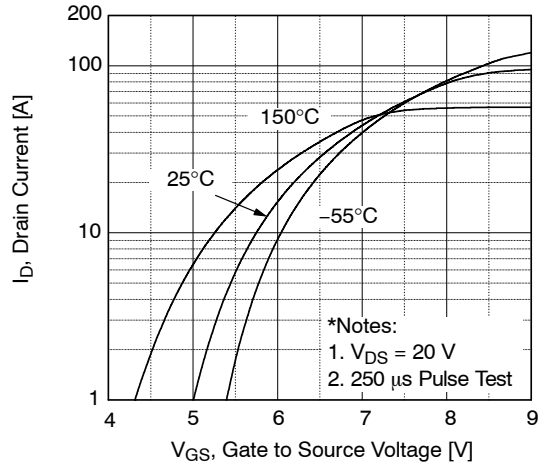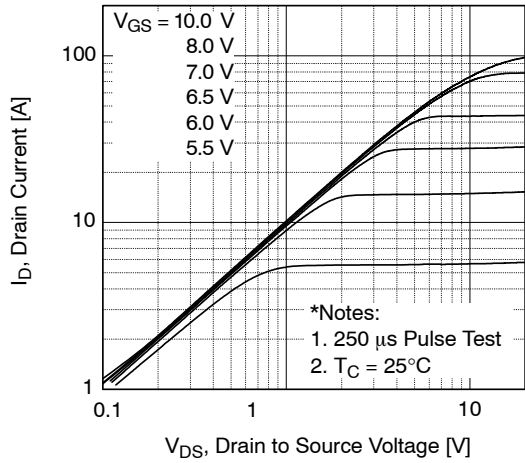
TYPICAL PERFORMANCE CHARACTERISTICS (continued)
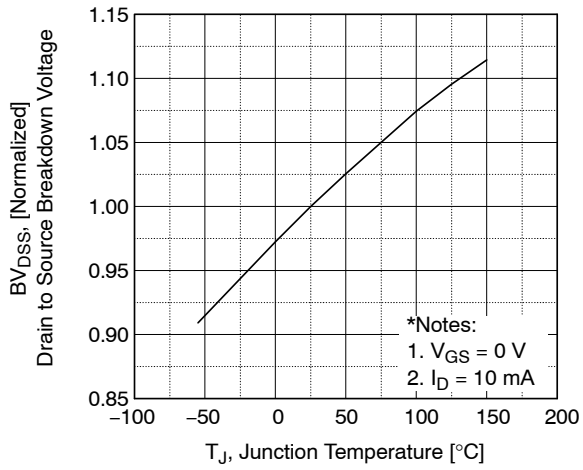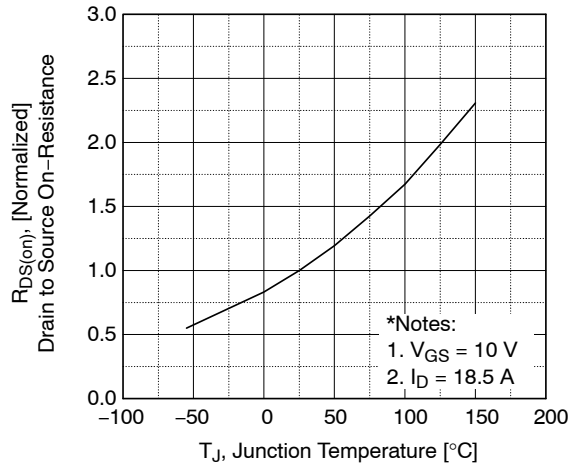

Figure 7. Breakdown Voltage Variation vs. Temperature

*Notes:
1. V_{GS} = 0 V
2. I_D = 10 mA

Figure 8. On-Resistance Variation vs. Temperature

*Notes:
1. V_{GS} = 10 V
2. I_D = 18.5 A
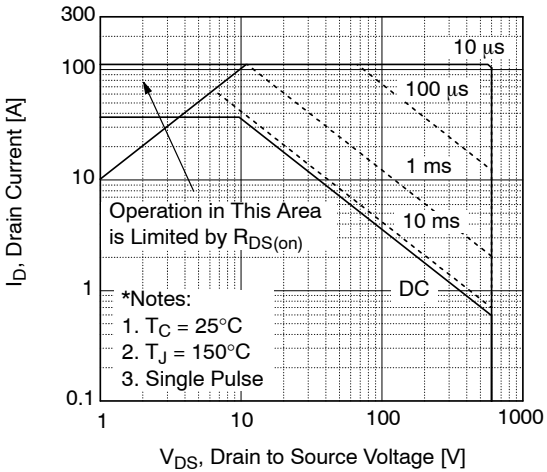
Figure 9. Maximum Safe Operation Area

Operation in This Area is Limited by $R_{DS(on)}$

*Notes:
1. T_C = 25°C
2. T_J = 150°C
3. Single Pulse
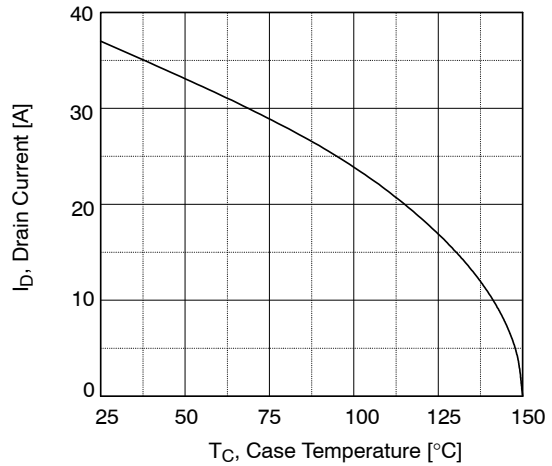
Figure 10. Maximum Drain Current vs. Case Temperature
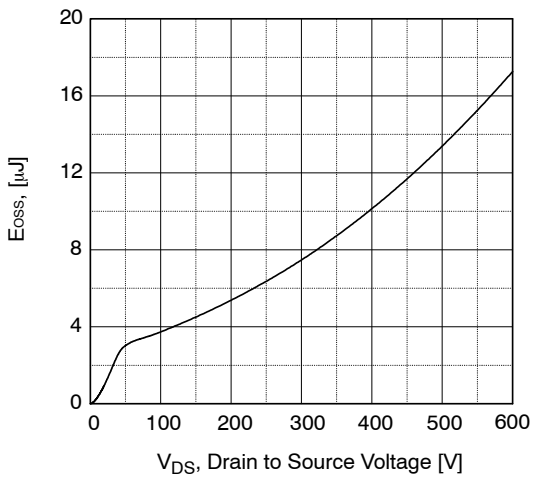
Figure 11. E_{OSS} vs. Drain to Source Voltage

TYPICAL PERFORMANCE CHARACTERISTICS (continued)
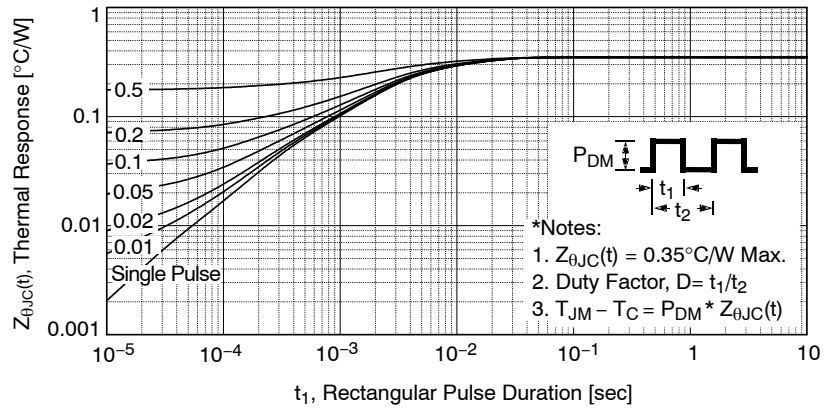
Figure 12. Transient Thermal Response Curve
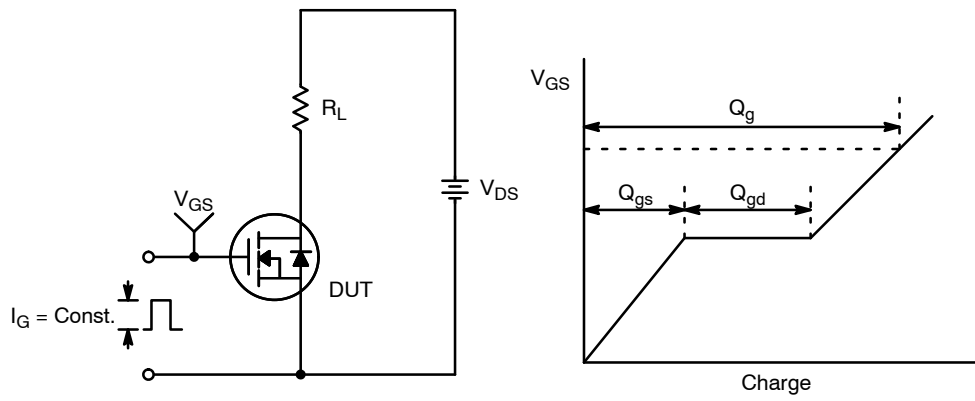
Figure 13. Gate Charge Test Circuit & Waveform
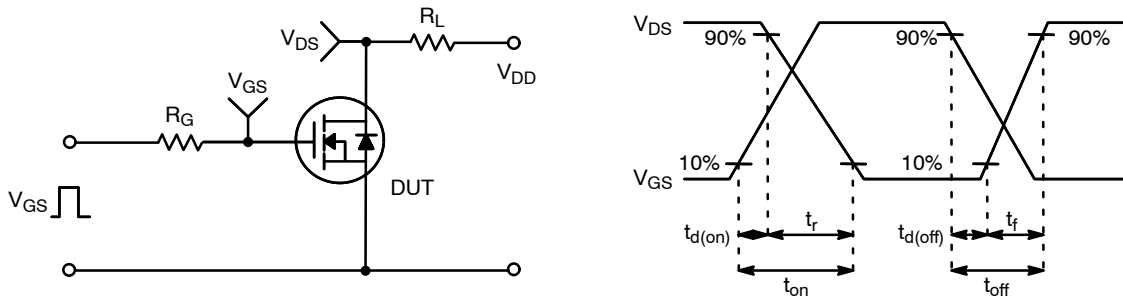
Figure 14. Resistive Switching Test Circuit & Waveforms

$$E_{AS} = \frac{1}{2}LI_{AS}{}^2$$
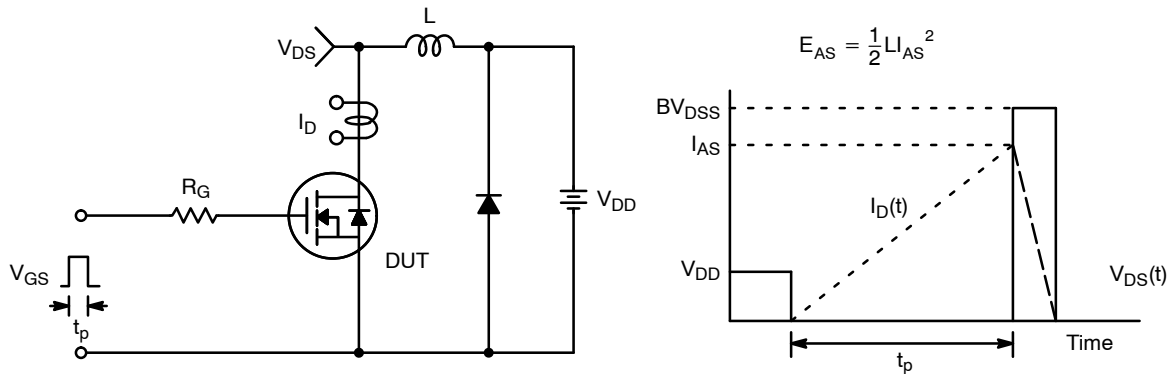
Figure 15. Unclamped Inductive Switching Test Circuit & Waveforms
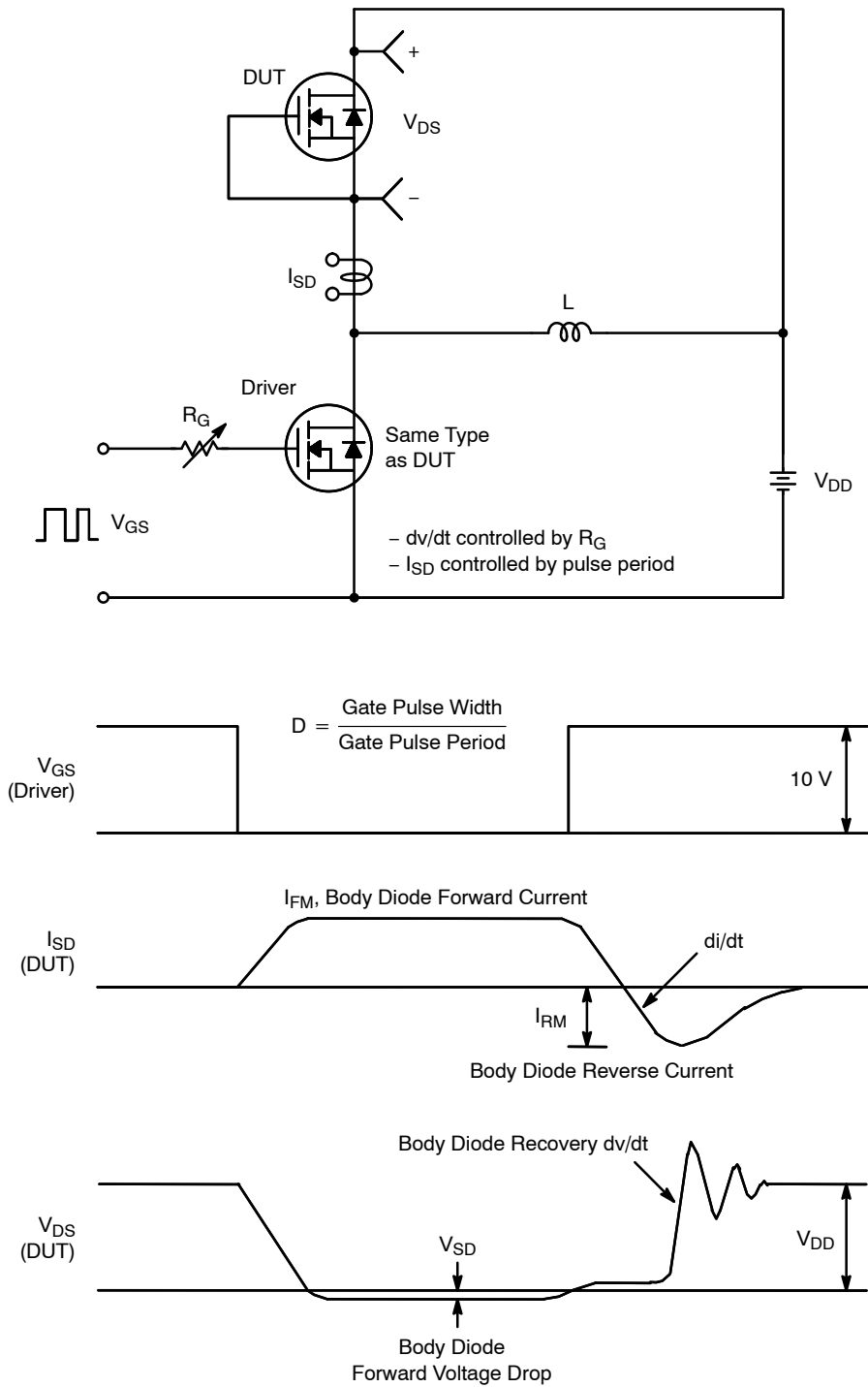
Figure 16. Peak Diode Recovery dv/dt Test Circuit & Waveforms

TO−247−3LD SHORT LEAD
CASE 340CK
ISSUE A

DATE 31 JAN 2019

A
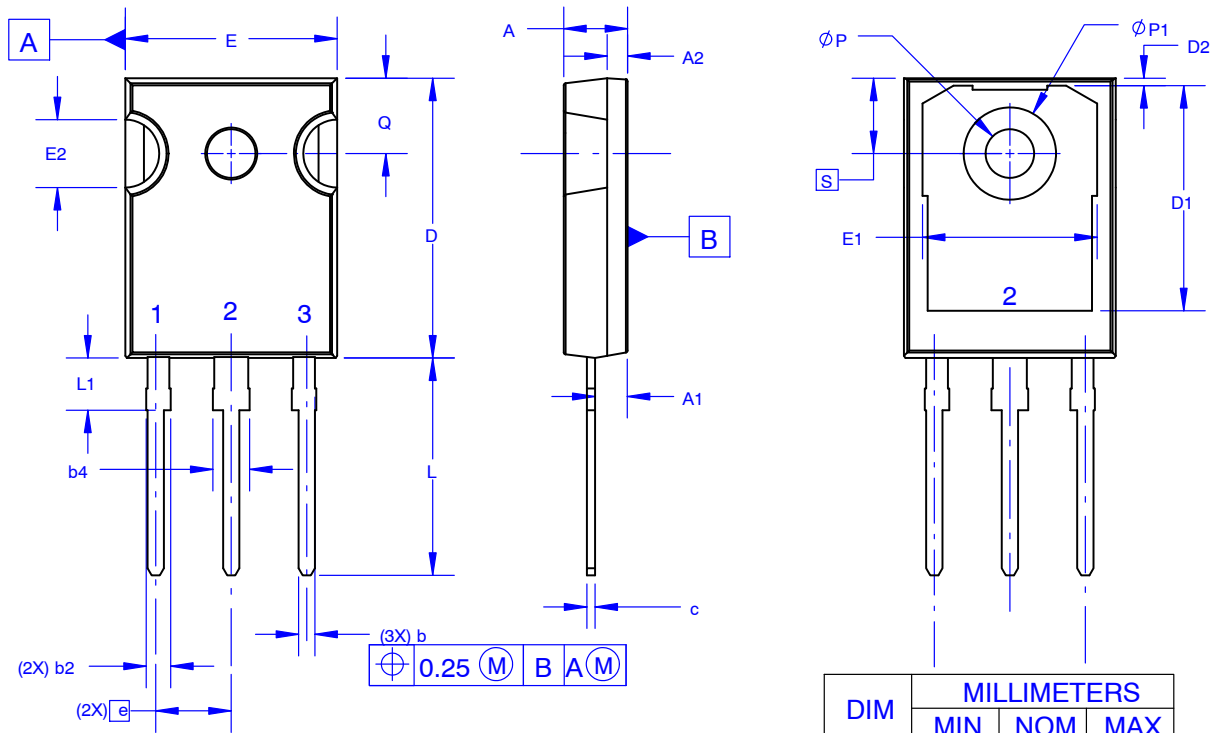
NOTES: UNLESS OTHERWISE SPECIFIED.

A. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSIONS.
B. ALL DIMENSIONS ARE IN MILLIMETERS.
C. DRAWING CONFORMS TO ASME Y14.5 - 2009.
D. DIMENSION A1 TO BE MEASURED IN THE REGION DEFINED BY L1.
E. LEAD FINISH IS UNCONTROLLED IN THE REGION DEFINED BY L1.

GENERIC MARKING DIAGRAM*

AYWWZZ
XXXXXXX
XXXXXXX
○
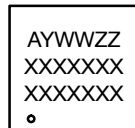
XXXX = Specific Device Code
A = Assembly Location
Y = Year
WW = Work Week
ZZ = Assembly Lot Code

*This information is generic. Please refer to device data sheet for actual part marking. Pb−Free indicator, "G" or microdot "▪", may or may not be present. Some products may not follow the Generic Marking.

DIM	MILLIMETERS		
	MIN	NOM	MAX
A	4.58	4.70	4.82
A1	2.20	2.40	2.60
A2	1.40	1.50	1.60
b	1.17	1.26	1.35
b2	1.53	1.65	1.77
b4	2.42	2.54	2.66
c	0.51	0.61	0.71
D	20.32	20.57	20.82
D1	13.08	~	~
D2	0.51	0.93	1.35
E	15.37	15.62	15.87
E1	12.81	~	~
E2	4.96	5.08	5.20
e	~	5.56	~
L	15.75	16.00	16.25
L1	3.69	3.81	3.93
ØP	3.51	3.58	3.65
ØP1	6.60	6.80	7.00
Q	5.34	5.46	5.58
S	5.34	5.46	5.58

ADDITIONAL INFORMATION

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